

Understanding multidimensional verification : where functional meets non-functional

Lai, Xinhui; Balakrishnan, Aneesh; Lange, Thomas; Jenihhin, Maksim; Ghasempouri, Tara; Raik, Jaan; Alexandrescu, Dan
Microprocessors and microsystems 2019 / art. 102867, 13 p. : ill <https://doi.org/10.1016/j.micpro.2019.102867> [Journal metrics at Scopus](#)
[Article at Scopus](#) [Journal metrics at WOS](#) [Article at WOS](#)